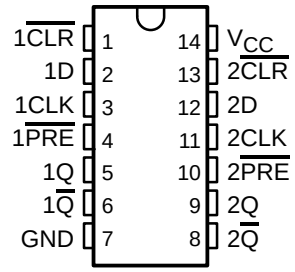
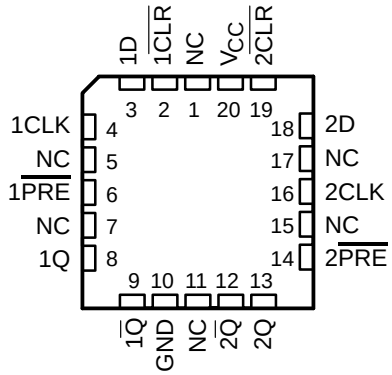
- **Operating Range 2-V to 5.5-V V_{CC}**
- ***EPIC***™ **(Enhanced-Performance Implanted CMOS) Process**
- **High Latch-Up Immunity Exceeds 250 mA Per JESD 17**
- **ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)**
- **Package Options Include Plastic Small-Outline (D), Shrink Small-Outline (DB), Thin Shrink Small-Outline (PW), and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs**

SN54AHC74 . . . J OR W PACKAGE
SN74AHC74 . . . D, DB, N, OR PW PACKAGE
(TOP VIEW)



SN54AHC74 . . . FK PACKAGE
(TOP VIEW)



NC – No internal connection

description

The ’AHC74 are dual positive-edge-triggered D-type flip-flops.

A low level at the preset ($\overline{PRE}$) or clear ($\overline{CLR}$) inputs sets or resets the outputs, regardless of the levels of the other inputs. When $\overline{PRE}$ and $\overline{CLR}$ are inactive (high), data at the data (D) input meeting the setup time requirements is transferred to the outputs on the positive-going edge of the clock pulse. Clock triggering occurs at a voltage level and is not directly related to the rise time of the clock pulse. Following the hold-time interval, data at the D input can be changed without affecting the levels at the outputs.

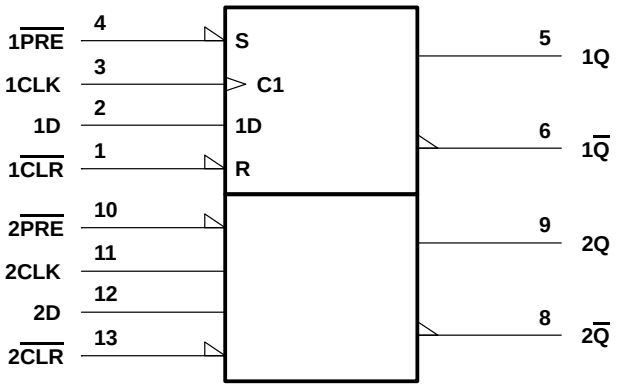
The SN54AHC74 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74AHC74 is characterized for operation from –40°C to 85°C.

FUNCTION TABLE

INPUTS				OUTPUTS	
$\overline{PRE}$	$\overline{CLR}$	CLK	D	Q	$\overline{Q}$
L	H	X	X	H	L
H	L	X	X	L	H
L	L	X	X	H†	H†
H	H	↑	H	H	L
H	H	↑	L	L	H
H	H	L	X	Q_0	$\overline{Q}_0$

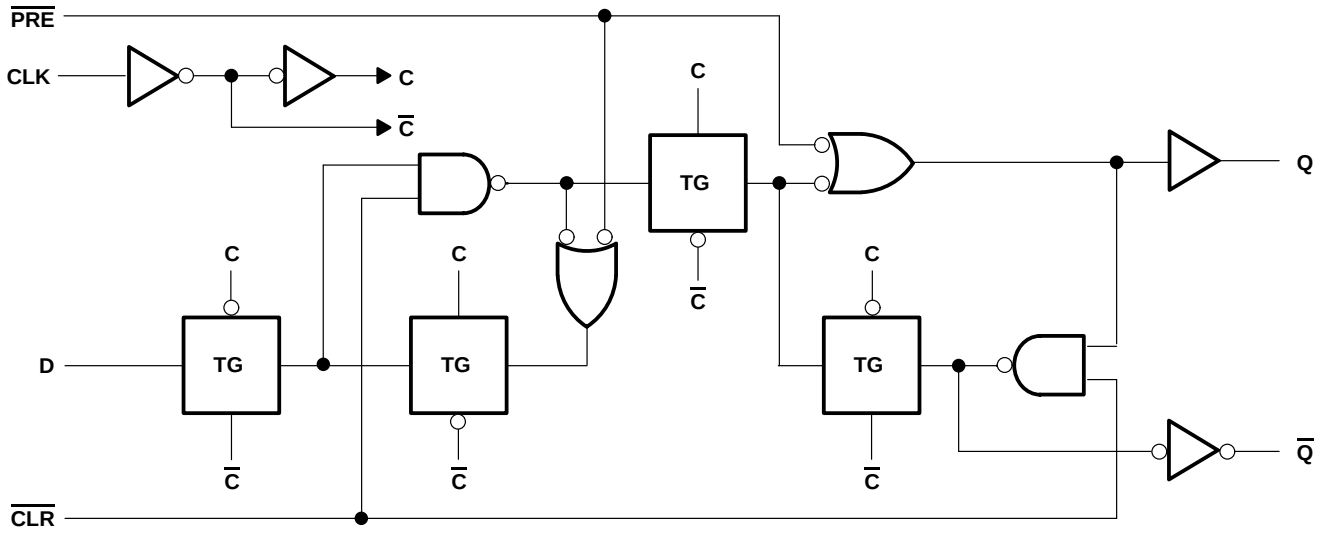
† This configuration is nonstable; that is, it does not persist when $\overline{PRE}$ or $\overline{CLR}$ returns to its inactive (high) level.

logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.
Pin numbers shown are for the D, DB, J, N, PW, and W packages.

logic diagram, each flip-flop (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V_{CC} . . . . . –0.5 V to 7 V
Input voltage range, V_I (see Note 1) . . . . . –0.5 V to 7 V
Output voltage range, V_O (see Note 1) . . . . . –0.5 V to V_{CC} + 0.5 V
Input clamp current, I_{IK} (V_I < 0) . . . . . –20 mA
Output clamp current, I_{OK} (V_O < 0 or V_O > V_{CC}) . . . . . ±20 mA
Continuous output current, I_O (V_O = 0 to V_{CC}) . . . . . ±25 mA
Continuous current through V_{CC} or GND . . . . . ±50 mA
Package thermal impedance, θ_{JA} (see Note 2): D package . . . . . 127°C/W
DB package . . . . . 158°C/W
N package . . . . . 78°C/W
PW package . . . . . 170°C/W
Storage temperature range, T_{stg} . . . . . –65°C to 150°C

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.

recommended operating conditions (see Note 3)

			SN54AHC74		SN74AHC74		UNIT
			MIN	MAX	MIN	MAX	
V_{CC}	Supply voltage		2	5.5	2	5.5	V
V_{IH}	High-level input voltage	V_{CC} = 2 V	1.5		1.5		V
		V_{CC} = 3 V	2.1		2.1		
		V_{CC} = 5.5 V	3.85		3.85		
V_{IL}	Low-level input voltage	V_{CC} = 2 V		0.5		0.5	V
		V_{CC} = 3 V		0.9		0.9	
		V_{CC} = 5.5 V		1.65		1.65	
V_I	Input voltage		0	5.5	0	5.5	V
V_O	Output voltage		0	V_{CC}	0	V_{CC}	V
I_{OH}	High-level output current	V_{CC} = 2 V		–50		–50	μA
		V_{CC} = 3.3 V ± 0.3 V		–4		–4	mA
		V_{CC} = 5 V ± 0.5 V		–8		–8	
I_{OL}	Low-level output current	V_{CC} = 2 V		50		50	μA
		V_{CC} = 3.3 V ± 0.3 V		4		4	mA
		V_{CC} = 5 V ± 0.5 V		8		8	
$\Delta t/\Delta v$	Input transition rise or fall rate	V_{CC} = 3.3 V ± 0.3 V		100		100	ns/V
		V_{CC} = 5 V ± 0.5 V		20		20	
T_A	Operating free-air temperature		–55	125	–40	85	°C

NOTE 3: Unused inputs must be held high or low to prevent them from floating.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V_{CC}	T_A = 25°C			SN54AHC74		SN74AHC74		UNIT
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
V_{OH}		I_{OH} = –50 μA	2 V	1.9	2		1.9		1.9		V
			3 V	2.9	3		2.9		2.9		
			4.5 V	4.4	4.5		4.4		4.4		
		I_{OH} = –4 mA	3 V	2.58			2.48		2.48		
		I_{OH} = –8 mA	4.5 V	3.94			3.8		3.8		
V_{OL}		I_{OL} = 50 μA	2 V			0.1		0.1		0.1	V
			3 V			0.1		0.1		0.1	
			4.5 V			0.1		0.1		0.1	
		I_{OL} = 4 mA	3 V			0.36		0.5		0.44	
		I_{OL} = 8 mA	4.5 V			0.36		0.5		0.44	
I_I	Data inputs	$V_I = V_{CC}$ or GND	5.5 V			±0.1		±1		±1	μA
	Control inputs					±0.1		±1		±1	
I_{CC}		$V_I = V_{CC}$ or GND, I_O = 0	5.5 V			2		20		20	μA
C_i		$V_I = V_{CC}$ or GND	5 V		2	10				10	pF

timing requirements over recommended operating free-air temperature range, V_{CC} = 3.3 V ± 0.3 V (unless otherwise noted) (see Figure 1)

			T_A = 25°C		SN54AHC74		SN74AHC74		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	
t_w	Pulse duration	$\overline{PRE}$ or $\overline{CLR}$ low	6		7		7		ns
		CLK	6		7		7		
t_{su}	Setup time before CLK↑	Data	6		7		7		ns
		$\overline{PRE}$ or $\overline{CLR}$ inactive	5		5		5		
t_h	Hold time, data after CLK↑		0.5		0.5		0.5		ns

timing requirements over recommended operating free-air temperature range, V_{CC} = 5 V ± 0.5 V (unless otherwise noted) (see Figure 1)

			T_A = 25°C		SN54AHC74		SN74AHC74		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	
t_w	Pulse duration	$\overline{PRE}$ or $\overline{CLR}$ low	5		5		5		ns
		CLK	5		5		5		
t_{su}	Setup time before CLK↑	Data	5		5		5		ns
		$\overline{PRE}$ or $\overline{CLR}$ inactive	3		3		3		
t_h	Hold time, data after CLK↑		0.5		0.5		0.5		ns

switching characteristics over recommended operating free-air temperature range, V_{CC} = 3.3 V ± 0.3 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	LOAD CAPACITANCE	SN54AHC74					UNIT
				T_A = 25°C			MIN	MAX	
				MIN	TYP	MAX			
f_{max}			C_L = 15 pF	80	125		70		MHz
			C_L = 50 pF	50	75		45		
t_{PLH}*	$\overline{PRE}$ or $\overline{CLR}$	Q or $\overline{Q}$	C_L = 15 pF		7.6	12.3	1	14.5	ns
t_{PHL}*					7.6	12.3	1	14.5	
t_{PLH}*	CLK	Q or $\overline{Q}$	C_L = 15 pF		6.7	11.9	1	14	ns
t_{PHL}*					6.7	11.9	1	14	
t_{PLH}	$\overline{PRE}$ or $\overline{CLR}$	Q or $\overline{Q}$	C_L = 50 pF		10.1	15.8	1	18	ns
t_{PHL}					10.1	15.8	1	18	
t_{PLH}	CLK	Q or $\overline{Q}$	C_L = 50 pF		9.2	15.4	1	17.5	ns
t_{PHL}					9.2	15.4	1	17.5	

* On products compliant to MIL-PRF-38535, this parameter is ensured but not production tested.

switching characteristics over recommended operating free-air temperature range, V_{CC} = 3.3 V ± 0.3 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	LOAD CAPACITANCE	SN74AHC74					UNIT
				T_A = 25°C			MIN	MAX	
				MIN	TYP	MAX			
f_{max}			C_L = 15 pF	80	125		70		MHz
			C_L = 50 pF	50	75		45		
t_{PLH}	$\overline{PRE}$ or $\overline{CLR}$	Q or $\overline{Q}$	C_L = 15 pF		7.6	12.3	1	14.5	ns
t_{PHL}					7.6	12.3	1	14.5	
t_{PLH}	CLK	Q or $\overline{Q}$	C_L = 15 pF		6.7	11.9	1	14	ns
t_{PHL}					6.7	11.9	1	14	
t_{PLH}	$\overline{PRE}$ or $\overline{CLR}$	Q or $\overline{Q}$	C_L = 50 pF		10.1	15.8	1	18	ns
t_{PHL}					10.1	15.8	1	18	
t_{PLH}	CLK	Q or $\overline{Q}$	C_L = 50 pF		9.2	15.4	1	17.5	ns
t_{PHL}					9.2	15.4	1	17.5	

switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V ± 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	LOAD CAPACITANCE	SN54AHC74					UNIT
				T_A = 25°C			MIN	MAX	
				MIN	TYP	MAX			
f_{max}			C_L = 15 pF	130	170		110		MHz
			C_L = 50 pF	90	115		75		
t_{PLH}*	$\overline{PRE}$ or $\overline{CLR}$	Q or $\overline{Q}$	C_L = 15 pF		4.8	7.7	1	9	ns
t_{PHL}*					4.8	7.7	1	9	
t_{PLH}*	CLK	Q or $\overline{Q}$	C_L = 15 pF		4.6	7.3	1	8.5	ns
t_{PHL}*					4.6	7.3	1	8.5	
t_{PLH}	$\overline{PRE}$ or $\overline{CLR}$	Q or $\overline{Q}$	C_L = 50 pF		6.3	9.7	1	11	ns
t_{PHL}					6.3	9.7	1	11	
t_{PLH}	CLK	Q or Q	C_L = 50 pF		6.1	9.3	1	10.5	ns
t_{PHL}					6.1	9.3	1	10.5	

* On products compliant to MIL-PRF-38535, this parameter is ensured but not production tested.

switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V ± 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	LOAD CAPACITANCE	SN74AHC74					UNIT
				T_A = 25°C			MIN	MAX	
				MIN	TYP	MAX			
f_{max}			C_L = 15 pF	130	170		110		MHz
			C_L = 50 pF	90	115		75		
t_{PLH}	$\overline{PRE}$ or $\overline{CLR}$	Q or $\overline{Q}$	C_L = 15 pF		4.8	7.7	1	9	ns
t_{PHL}					4.8	7.7	1	9	
t_{PLH}	CLK	Q or $\overline{Q}$	C_L = 15 pF		4.6	7.3	1	8.5	ns
t_{PHL}					4.6	7.3	1	8.5	
t_{PLH}	$\overline{PRE}$ or $\overline{CLR}$	Q or $\overline{Q}$	C_L = 50 pF		6.3	9.7	1	11	ns
t_{PHL}					6.3	9.7	1	11	
t_{PLH}	CLK	Q or Q	C_L = 50 pF		6.1	9.3	1	10.5	ns
t_{PHL}					6.1	9.3	1	10.5	

noise characteristics, V_{CC} = 5 V, C_L = 50 pF, T_A = 25°C (see Note 4)

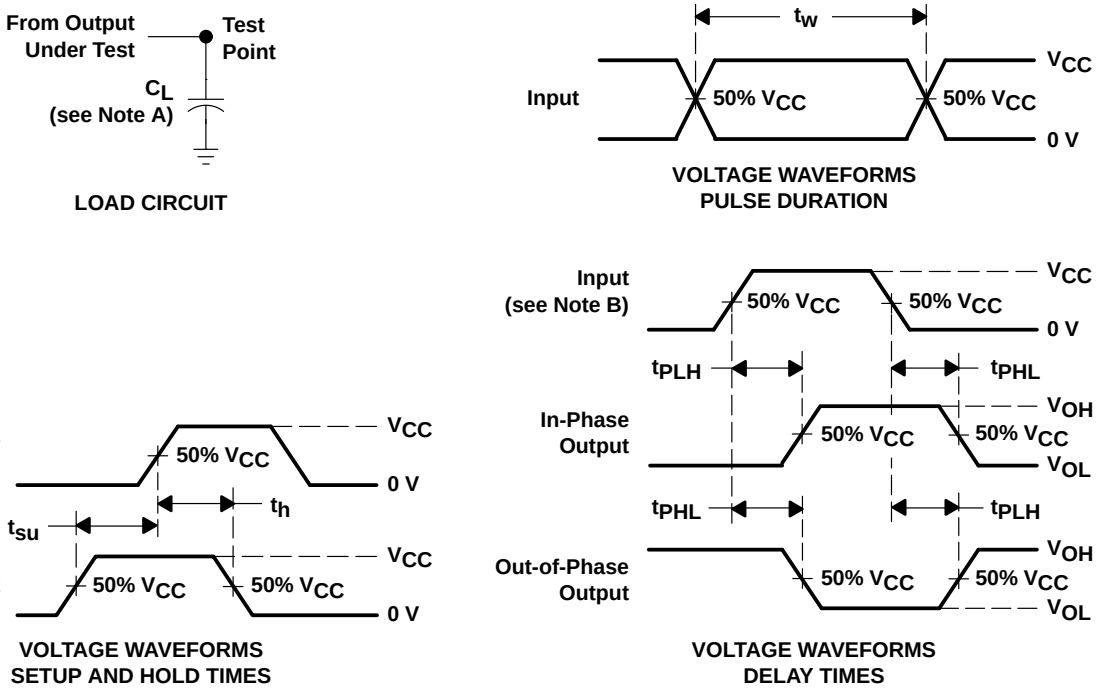
PARAMETER		SN74AHC74		UNIT
		MIN	MAX	
$V_{OL(P)}$	Quiet output, maximum dynamic V_{OL}		0.8	V
$V_{OL(V)}$	Quiet output, minimum dynamic V_{OL}	4.7	–0.8	V
$V_{IH(D)}$	High-level dynamic input voltage	3.5		V
$V_{IL(D)}$	Low-level dynamic input voltage		1.5	V

NOTE 4: Characteristics are determined during product characterization and ensured by design for surface-mount packages only.

operating characteristics, V_{CC} = 5 V, T_A = 25°C

PARAMETER		TEST CONDITIONS		TYP	UNIT
C_{pd}	Power dissipation capacitance	No load,	f = 1 MHz	32	pF

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.
B. All input pulses are supplied by generators having the following characteristics: PRR ≤ 1 MHz, Z_O = 50 Ω, t_r = 3 ns, t_f = 3 ns.
C. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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